

Notice of References Cited	Application/Control No. 09/773,537	Applicant(s)/Patent Under Reexamination HIRAYAMA ET AL.	
	Examiner Yubin Hung	Art Unit 2625	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,522,977	02-2003	Corrigan et al.	702/32
	B	US-4,479,718	10-1984	Alman, David H.	356/405
	C	US-4,813,000	03-1989	Wyman et al.	382/165
	D	US-5,387,977	02-1995	Berg et al.	356/407
	E	US-6,539,325	03-2003	Numata et al.	702/127
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	James E. Proctor & P. Yvonne Barnes, "NIST High Accuracy Reference Reflectometer-Spectrophotometer," J. Research of the NIST, Vol. 101, No. 5, Sep.-Oct. 1996, pp. 619-627
	V	Li-Piin Sung, Maria E. Nadal, Mary E. McKnight & Egon Marx, "Optical Reflectance of Metallic Coatings: Effect of Aluminum Flake Orientation," J. Coatings Technology, Vol. 74, No. 932, Sep. 2002, pp. 55-63
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.